

4.4 Utilization categories

The utilization category of a circuit-breaker shall be stated with reference to whether or not it is specifically intended for selectivity by means of an intentional time delay with respect to other circuit-breakers in series on the load side, under short-circuit conditions (see Figure A.3).

Attention is drawn to the differences of the tests applying to the two utilization categories (see Table 9 and 8.3.4, 8.3.5, 8.3.6 and 8.3.8).

Utilization categories are defined in Table 4.

Table 4 – Utilization categories

Utilization category	Application with respect to selectivity
A	Circuit-breakers not specifically intended for selectivity under short-circuit conditions with respect to other short-circuit protective devices in series on the load side, i.e. without an intentional short-time delay provided for selectivity under short-circuit conditions, and therefore without a short-time withstand current rating according to 4.3.5.4.
B	Circuit-breakers specifically intended for selectivity under short-circuit conditions with respect to other short-circuit protective devices in series on the load side, i.e. with an intentional short-time delay (which may be adjustable), provided for selectivity under short-circuit conditions. Such circuit-breakers have a short-time withstand current rating according to 4.3.5.4. NOTE Selectivity is not necessarily ensured up to the ultimate short-circuit breaking capacity of the circuit-breakers (for example in the case of operation of an instantaneous release) but at least up to the value specified in Table 3.
NOTE 1 The power factor or time constant associated with each value of rated short-circuit current is given in Table 11 (see 8.3.2.2.4 and 8.3.2.2.5). NOTE 2 Attention is drawn to the different requirements for the minimum required percentage of I_{cs} for utilization categories A and B, in accordance with Table 1. NOTE 3 A circuit-breaker of utilization category A may have an intentional short-time delay provided for selectivity under conditions other than those of short circuit, with a short-time withstand current less than that according to Table 3. In that case, the tests include test sequence IV (see 8.3.6) at the assigned short-time withstand current.	